

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/743,592	PARKER ET AL.	
Examiner		Art Unit		Page 1 of 1
BEN H. LIU		2416		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,822,299 A	10-1998	Goodman, David Michael	370/228
*	B	US-5,844,887 A	12-1998	Oren et al.	370/218
*	C	US-6,332,198 B1	12-2001	Simons et al.	714/6
*	D	US-6,359,859 B1	03-2002	Brolin et al.	370/218
*	E	US-2003/0043737 A1	03-2003	Tada, Katsuyuki	370/218
*	F	US-2003/0117952 A1	06-2003	Ueno et al.	370/228
*	G	US-2004/0085895 A1	05-2004	Zettinger et al.	370/220
*	H	US-6,771,852 B2	08-2004	Hemenway et al.	385/24
*	I	US-6,859,430 B1	02-2005	Frank et al.	370/216
*	J	US-6,906,999 B1	06-2005	Schulz, Jeff	370/218
*	K	US-7,058,010 B2	06-2006	Chidambaran et al.	370/218
*	L	US-7,133,357 B2	11-2006	Tada, Katsuyuki	370/219
*	M	US-7,272,116 B1	09-2007	Houchen, Stephen H.	370/258

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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